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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	576
Number of Logic Elements/Cells	1368
Total RAM Bits	18432
Number of I/O	192
Number of Gates	30000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs30-4pq240c

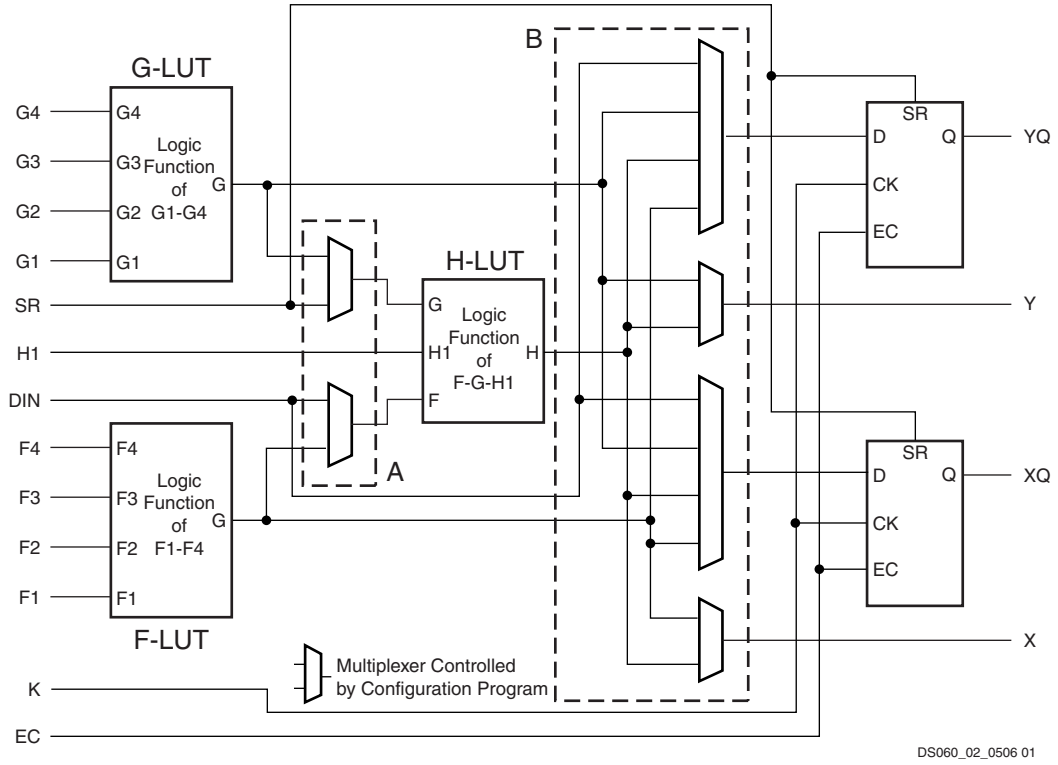


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS**, page 20.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

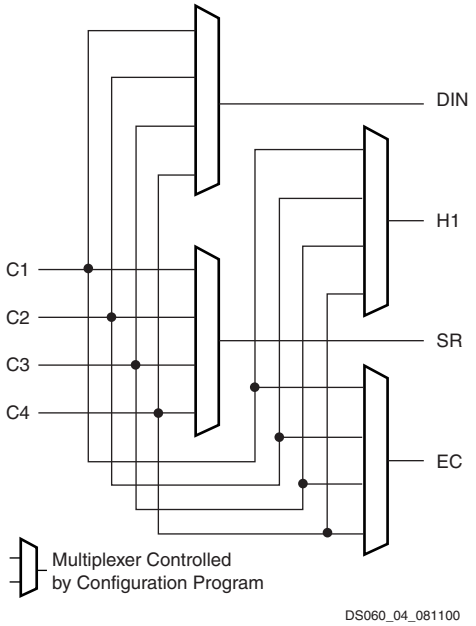


Figure 4: **CLB Control Signal Interface**

The four internal control signals are:

- EC: Enable Clock
- SR: Asynchronous Set/Reset or H function generator Input 0
- DIN: Direct In or H function generator Input 2
- H1: H function generator Input 1.

Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals. Figure 6 shows a simplified functional block diagram of the Spartan/XL FPGA IOB.

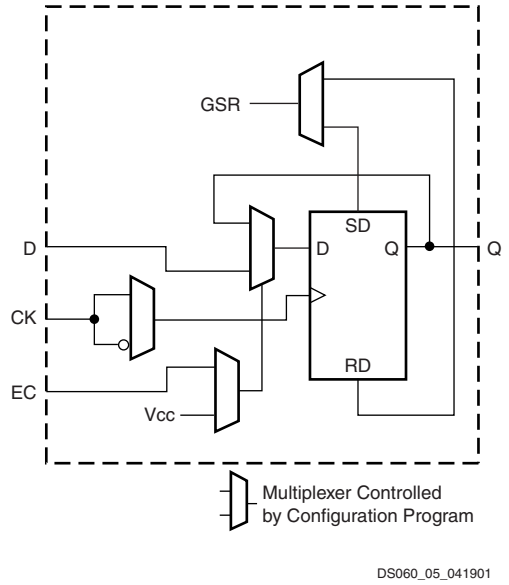


Figure 5: **IOB Flip-Flop/Latch Functional Block Diagram**

IOB Input Signal Path

The input signal to the IOB can be configured to either go directly to the routing channels (via I1 and I2 in Figure 6) or to the input register. The input register can be programmed as either an edge-triggered flip-flop or a level-sensitive latch. The functionality of this register is shown in Table 3, and a simplified block diagram of the register can be seen in Figure 5.

Table 3: **Input Register Functionality**

Mode	CK	EC	D	Q
Power-Up or GSR	X	X	X	SR
Flip-Flop	⌐	1*	D	D
	0	X	X	Q
Latch	1	1*	X	Q
	0	1*	D	D
Both	X	0	X	Q

Legend:

X	Don't care.
⌐	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)

Table 4: **Supported Sources for Spartan/XL Inputs**

Source	Spartan Inputs		Spartan-XL Inputs
	5V, TTL	5V, CMOS	3.3V CMOS
Any device, V_{CC} = 3.3V, CMOS outputs	√	Unreliable Data	√
Spartan family, V_{CC} = 5V, TTL outputs	√		√
Any device, V_{CC} = 5V, TTL outputs ($V_{OH} \leq 3.7V$)	√		√
Any device, V_{CC} = 5V, CMOS outputs	√	√	√ (default mode)

Spartan-XL Family V_{CC} Clamping

Spartan-XL FPGAs have an optional clamping diode connected from each I/O to V_{CC}. When enabled they clamp ringing transients back to the 3.3V supply rail. This clamping action is required in 3.3V PCI applications. V_{CC} clamping is a global option affecting all I/O pins.

Spartan-XL devices are fully 5V TTL I/O compatible if V_{CC} clamping is not enabled. With V_{CC} clamping enabled, the Spartan-XL devices will begin to clamp input voltages to one diode voltage drop above V_{CC}. If enabled, TTL I/O compatibility is maintained but full 5V I/O tolerance is sacrificed. The user may select either 5V tolerance (default) or 3.3V PCI compatibility. In both cases negative voltage is clamped to one diode voltage drop below ground.

Spartan-XL devices are compatible with TTL, LVTTL, PCI 3V, PCI 5V and LVCMOS signalling. The various standards are illustrated in Table 5.

Table 5: **I/O Standards Supported by Spartan-XL FPGAs**

Signaling Standard	VCC Clamping	Output Drive	$V_{IH\ MAX}$	$V_{IH\ MIN}$	$V_{IL\ MAX}$	$V_{OH\ MIN}$	$V_{OL\ MAX}$
TTL	Not allowed	12/24 mA	5.5	2.0	0.8	2.4	0.4
LVTTL	OK	12/24 mA	3.6	2.0	0.8	2.4	0.4
PCI5V	Not allowed	24 mA	5.5	2.0	0.8	2.4	0.4
PCI3V	Required	12 mA	3.6	50% of V_{CC}	30% of V_{CC}	90% of V_{CC}	10% of V_{CC}
LVCMOS 3V	OK	12/24 mA	3.6	50% of V_{CC}	30% of V_{CC}	90% of V_{CC}	10% of V_{CC}

Additional Fast Capture Input Latch (Spartan-XL Family Only)

The Spartan-XL family OB has an additional optional latch on the input. This latch is clocked by the clock used for the output flip-flop rather than the input clock. Therefore, two different clocks can be used to clock the two input storage elements. This additional latch allows the fast capture of input data, which is then synchronized to the internal clock by the IOB flip-flop or latch.

To place the Fast Capture latch in a design, use one of the special library symbols, ILFFX or ILFLX. ILFFX is a transparent-Low Fast Capture latch followed by an active High input flip-flop. ILFLX is a transparent Low Fast Capture latch followed by a transparent High input latch. Any of the clock inputs can be inverted before driving the library element, and the inverter is absorbed into the IOB.

IOB Output Signal Path

Output signals can be optionally inverted within the IOB, and can pass directly to the output buffer or be stored in an edge-triggered flip-flop and then to the output buffer. The functionality of this flip-flop is shown in Table 6.

Table 6: **Output Flip-Flop Functionality**

Mode	Clock	Clock Enable	T	D	Q
Power-Up or GSR	X	X	0*	X	SR
Flip-Flop	X	0	0*	X	Q
	⌐	1*	0*	D	D
	X	X	1	X	Z
	0	X	0*	X	Q

Legend:

X	Don't care
⌐	Rising edge (clock not inverted).
SR	Set or Reset value. Reset is default.
0*	Input is Low or unconnected (default value)
1*	Input is High or unconnected (default value)
Z	3-state

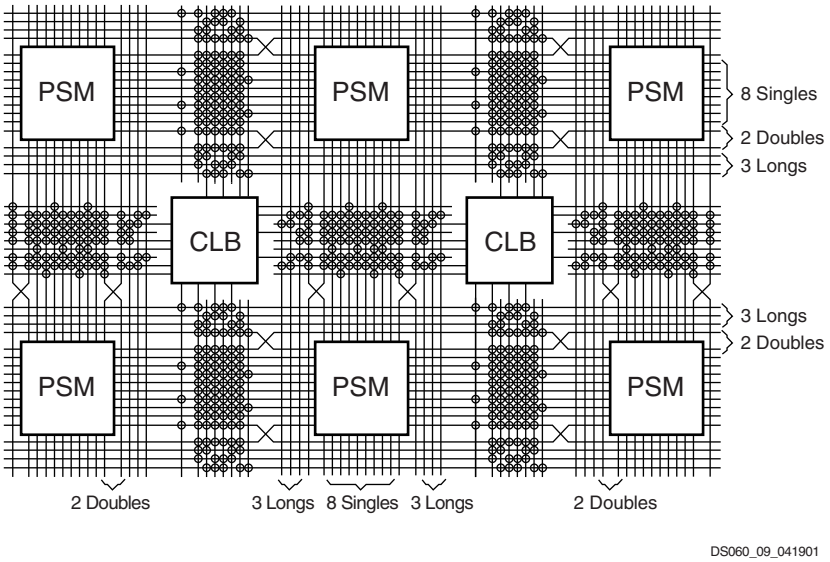


Figure 8: **Spartan/XL CLB Routing Channels and Interface Block Diagram**

CLB Interface

A block diagram of the CLB interface signals is shown in Figure 9. The input signals to the CLB are distributed evenly on all four sides providing maximum routing flexibility. In general, the entire architecture is symmetrical and regular. It is well suited to established placement and routing algorithms. Inputs, outputs, and function generators can freely swap positions within a CLB to avoid routing congestion during the placement and routing operation. The exceptions are the clock (K) input and CIN/COUT signals. The K input is routed to dedicated global vertical lines as well as four single-length lines and is on the left side of the CLB. The CIN/COUT signals are routed through dedicated interconnects which do not interfere with the general routing structure. The output signals from the CLB are available to drive both vertical and horizontal channels.

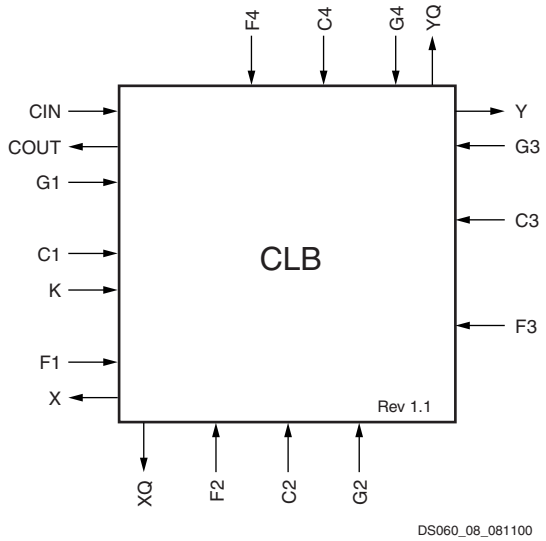


Figure 9: **CLB Interconnect Signals**

Programmable Switch Matrices

The horizontal and vertical single- and double-length lines intersect at a box called a programmable switch matrix (PSM). Each PSM consists of programmable pass transistors used to establish connections between the lines (see Figure 10).

For example, a single-length signal entering on the right side of the switch matrix can be routed to a single-length line on the top, left, or bottom sides, or any combination thereof, if multiple branches are required. Similarly, a double-length signal can be routed to a double-length line on any or all of the other three edges of the programmable switch matrix.

Single-Length Lines

Single-length lines provide the greatest interconnect flexibility and offer fast routing between adjacent blocks. There are eight vertical and eight horizontal single-length lines associated with each CLB. These lines connect the switching matrices that are located in every row and column of CLBs. Single-length lines are connected by way of the programmable switch matrices, as shown in Figure 10. Routing connectivity is shown in Figure 8.

Single-length lines incur a delay whenever they go through a PSM. Therefore, they are not suitable for routing signals for long distances. They are normally used to conduct signals within a localized area and to provide the branching for nets with fanout greater than one.

- The 16 x 1 single-port configuration contains a RAM array with 16 locations, each one-bit wide. One 4-bit address decoder determines the RAM location for write and read operations. There is one input for writing data and one output for reading data, all at the selected address.
- The (16 x 1) x 2 single-port configuration combines two 16 x 1 single-port configurations (each according to the preceding description). There is one data input, one data output and one address decoder for each array. These arrays can be addressed independently.
- The 32 x 1 single-port configuration contains a RAM array with 32 locations, each one-bit wide. There is one data input, one data output, and one 5-bit address decoder.
- The dual-port mode 16 x 1 configuration contains a RAM array with 16 locations, each one-bit wide. There are two 4-bit address decoders, one for each port. One port consists of an input for writing and an output for reading, all at a selected address. The other port consists of one output for reading from an independently selected address.

The appropriate choice of RAM configuration mode for a given design should be based on timing and resource requirements, desired functionality, and the simplicity of the design process. Selection criteria include the following: Whereas the 32 x 1 single-port, the (16 x 1) x 2 single-port, and the 16 x 1 dual-port configurations each use one entire CLB, the 16 x 1 single-port configuration uses only one half of a CLB. Due to its simultaneous read/write capability, the dual-port RAM can transfer twice as much data as the single-port RAM, which permits only one data operation at any given time.

CLB memory configuration options are selected by using the appropriate library symbol in the design entry.

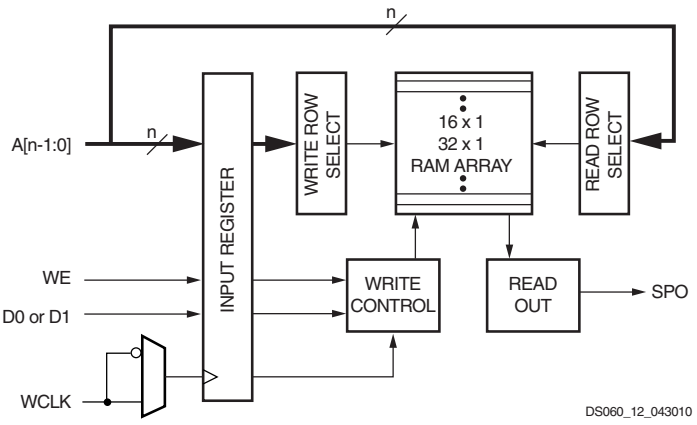
Single-Port Mode

There are three CLB memory configurations for the single-port RAM: 16 x 1, (16 x 1) x 2, and 32 x 1, the functional organization of which is shown in Figure 12.

The single-port RAM signals and the CLB signals (Figure 2, page 4) from which they are originally derived are shown in Table 9.

Table 9: **Single-Port RAM Signals**

RAM Signal	Function	CLB Signal
D0 or D1	Data In	DIN or H1
A[3:0]	Address	F[4:1] or G[4:1]
A4 (32 x 1 only)	Address	H1
WE	Write Enable	SR
WCLK	Clock	K
SPO	Single Port Out (Data Out)	F_{OUT} or G_{OUT}



Notes:
1. The (16 x 1) x 2 configuration combines two 16 x 1 single-port RAMs, each with its own independent address bus and data input. The same WE and WCLK signals are connected to both RAMs.
2. n = 4 for the 16 x 1 and (16 x 1) x 2 configurations. n = 5 for the 32 x 1 configuration.

Figure 12: **Logic Diagram for the Single-Port RAM**

Writing data to the single-port RAM is essentially the same as writing to a data register. It is an edge-triggered (synchronous) operation performed by applying an address to the A inputs and data to the D input during the active edge of WCLK while WE is High.

The timing relationships are shown in Figure 13. The High logic level on WE enables the input data register for writing. The active edge of WCLK latches the address, input data, and WE signals. Then, an internal write pulse is generated that loads the data into the memory cell.

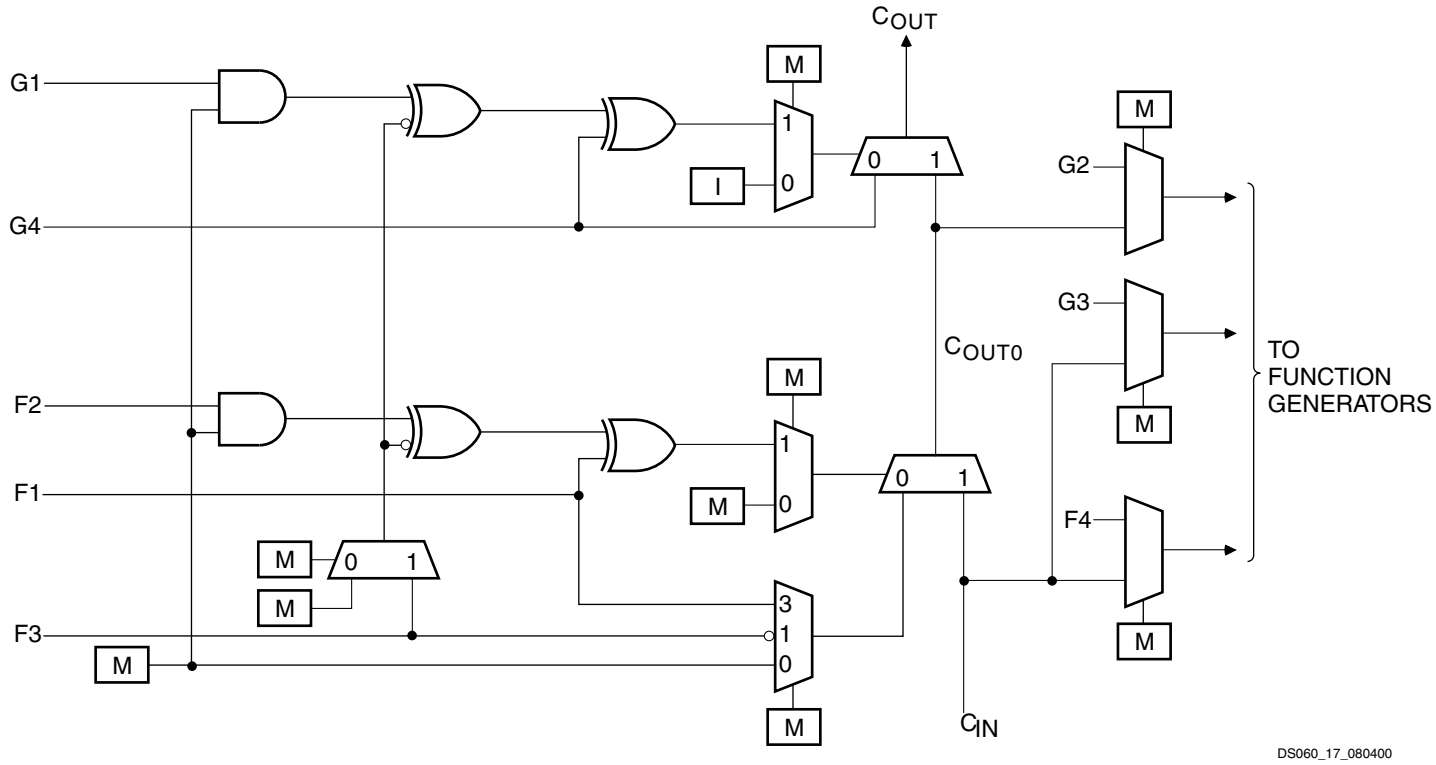


Figure 17: **Detail of Spartan/XL Dedicated Carry Logic**

3-State Long Line Drivers

A pair of 3-state buffers is associated with each CLB in the array. These 3-state buffers (BUFT) can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources.

There is a weak keeper at each end of these two horizontal longlines. This circuit prevents undefined floating levels. However, it is overridden by any driver.

The buffer enable is an active High 3-state (i.e., an active Low enable), as shown in Table 11.

Three-State Buffer Example

Figure 18 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active High 3-state (T) is identical to an active Low output enable, as shown in Table 11.

Table 11: **Three-State Buffer Functionality**

IN	T	OUT
X	1	Z
IN	0	IN

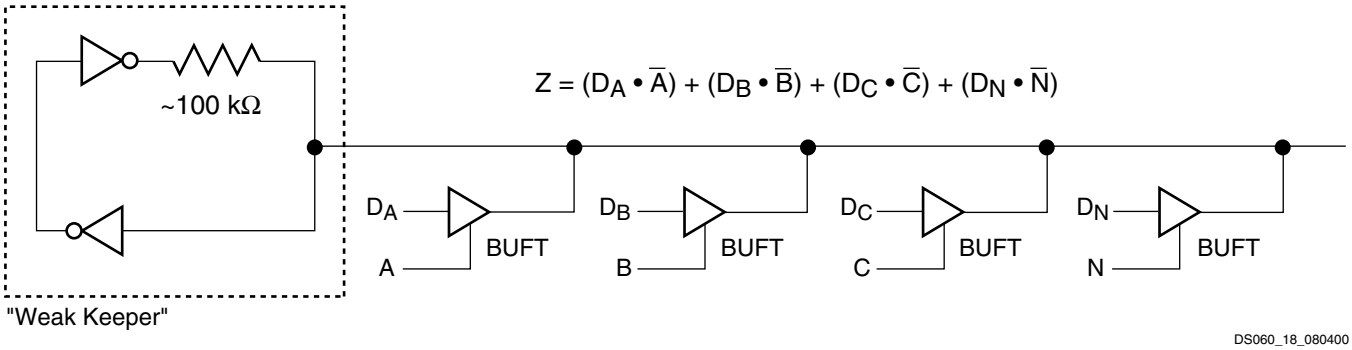
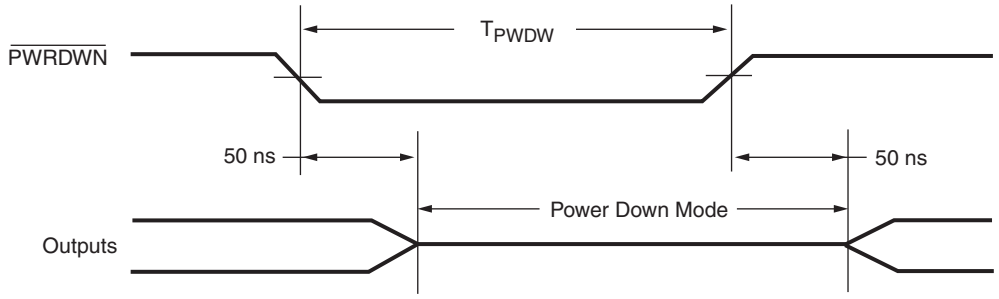


Figure 18: **3-state Buffers Implement a Multiplexer**



Description	Symbol	Min
Power Down Time	T_{PWD}	50 ns
Power Down Pulse Width	T_{PWDW}	50 ns

DS060_23_041901

Figure 23: **$\overline{\text{PWRDWN}}$ Pulse Timing**

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the $\overline{\text{PWRDWN}}$ pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the $\overline{\text{PWRDWN}}$ signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if $\overline{\text{PWRDWN}}$ is asserted before configuration is completed, the $\overline{\text{INIT}}$ pin will not indicate status information.

Note that the $\overline{\text{PWRDWN}}$ pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

3V Spartan-XL devices have three configuration modes.

- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 KΩ or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during con-

Table 16: **Spartan/XL Data Stream Formats**

Data Type	Serial Modes (D0...)	Express Mode (D0-D7) (Spartan-XL only)
Fill Byte	11111111b	FFFFh
Preamble Code	0010b	11110010b
Length Count	COUNT[23:0]	COUNT[23:0](1)
Fill Bits	1111b	-
Field Check Code	-	11010010b
Start Field	0b	11111110b(2)
Data Frame	DATA[n–1:0]	DATA[n–1:0]
CRC or Constant Field Check	xxxx (CRC) or 0110b	11010010b
Extend Write Cycle	-	FFD2FFFFFFh
Postamble	01111111b	-
Start-Up Bytes(3)	FFh	FFFFFFFFFFFFFFh

Legend:

Unshaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

Notes:
1. Not used by configuration logic.
2. 11111111b for XCS40XL only.
3. Development system may add more start-up bytes.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The Spartan-XL family Express mode only supports non-CRC error checking. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading before DONE goes High, and the pulling down of the $\overline{\text{INIT}}$ pin. In Master serial mode, CCLK continues to operate externally. The user must detect $\overline{\text{INIT}}$ and initialize a new configuration by pulsing the $\overline{\text{PROGRAM}}$ pin Low or cycling V_{CC}.

Cyclic Redundancy Check (CRC) for Configuration and Readback

The Cyclic Redundancy Check is a method of error detection in data transmission applications. Generally, the transmitting system performs a calculation on the serial bitstream. The result of this calculation is tagged onto the data stream as additional check bits. The receiving system performs an identical calculation on the bitstream and compares the result with the received checksum.

Each data frame of the configuration bitstream has four error bits at the end, as shown in Table 16. If a frame data error is detected during the loading of the FPGA, the configuration process with a potentially corrupted bitstream is terminated. The FPGA pulls the $\overline{\text{INIT}}$ pin Low and goes into a Wait state.

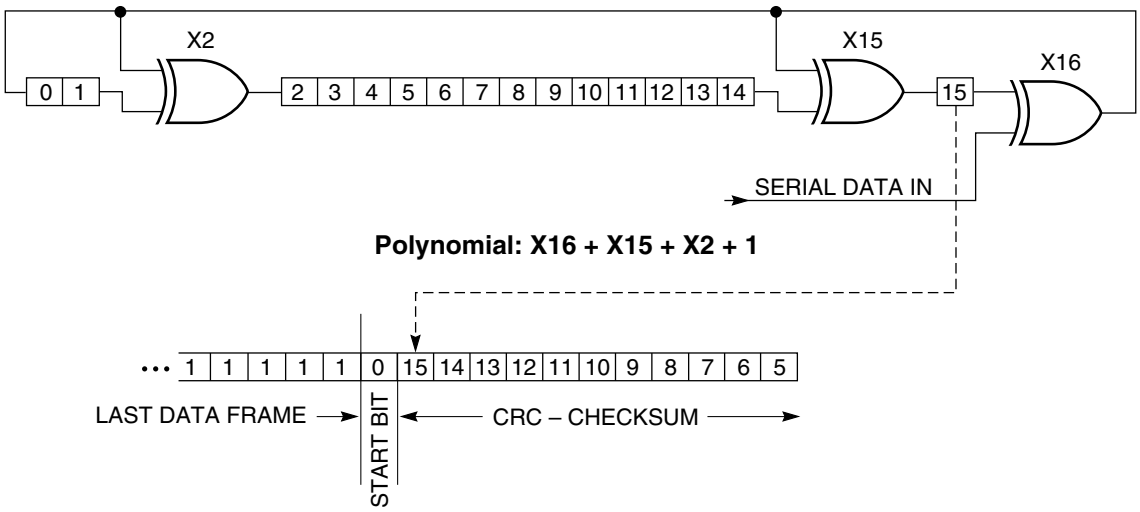


Figure 29: **Circuit for Generating CRC-16**

Configuration Sequence

There are four major steps in the Spartan/XL FPGA power-up configuration sequence.

- Configuration Memory Clear
- Initialization
- Configuration
- Start-up

The full process is illustrated in Figure 30.

Configuration Memory Clear

When power is first applied or is reapplied to an FPGA, an internal circuit forces initialization of the configuration logic. When V_{CC} reaches an operational level, and the circuit passes the write and read test of a sample pair of configuration bits, a time delay is started. This time delay is nominally 16 ms. The delay is four times as long when in Master Serial Mode to allow ample time for all slaves to reach a stable V_{CC}. When all $\overline{INIT}$ pins are tied together, as recommended, the longest delay takes precedence. Therefore, devices with different time delays can easily be mixed and matched in a daisy chain.

This delay is applied only on power-up. It is not applied when reconfiguring an FPGA by pulsing the $\overline{PROGRAM}$ pin Low. During this time delay, or as long as the $\overline{PROGRAM}$ input is asserted, the configuration logic is held in a Configuration Memory Clear state. The configuration-memory frames are consecutively initialized, using the internal oscillator.

At the end of each complete pass through the frame addressing, the power-on time-out delay circuitry and the level of the $\overline{PROGRAM}$ pin are tested. If neither is asserted, the logic initiates one additional clearing of the configuration frames and then tests the $\overline{INIT}$ input.

Initialization

During initialization and configuration, user pins HDC, $\overline{LDC}$, $\overline{INIT}$ and DONE provide status outputs for the system interface. The outputs $\overline{LDC}$, $\overline{INIT}$ and DONE are held Low and HDC is held High starting at the initial application of power.

The open drain $\overline{INIT}$ pin is released after the final initialization pass through the frame addresses. There is a deliberate delay before a Master-mode device recognizes an inactive $\overline{INIT}$. Two internal clocks after the $\overline{INIT}$ pin is recognized as High, the device samples the MODE pin to determine the configuration mode. The appropriate interface lines become active and the configuration preamble and data can be loaded.

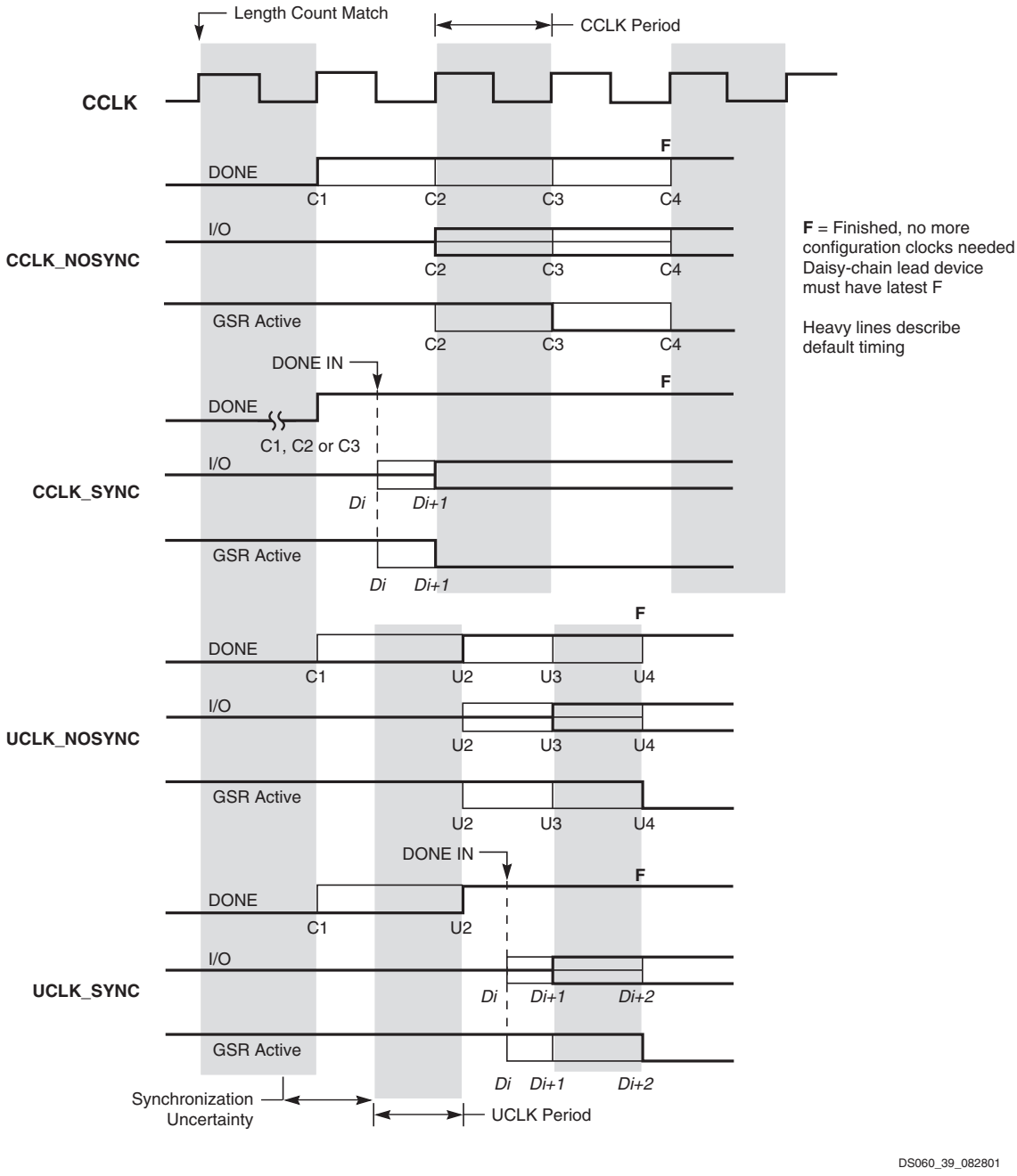


Figure 31: **Start-up Timing**

Configuration Through the Boundary Scan Pins

Spartan/XL devices can be configured through the boundary scan pins. The basic procedure is as follows:

- Power up the FPGA with $\overline{\text{INIT}}$ held Low (or drive the $\overline{\text{PROGRAM}}$ pin Low for more than 300 ns followed by a High while holding $\overline{\text{INIT}}$ Low). Holding $\overline{\text{INIT}}$ Low allows enough time to issue the CONFIG command to the FPGA. The pin can be used as I/O after configuration if a resistor is used to hold $\overline{\text{INIT}}$ Low.
- Issue the CONFIG command to the TMS input.
- Wait for $\overline{\text{INIT}}$ to go High.
- Sequence the boundary scan Test Access Port to the SHIFT-DR state.
- Toggle TCK to clock data into TDI pin.

The user must account for all TCK clock cycles after $\overline{\text{INIT}}$ goes High, as all of these cycles affect the Length Count compare.

For more detailed information, refer to the Xilinx application note, "*Boundary Scan in FPGA Devices*." This application note applies to Spartan and Spartan-XL devices.

Spartan Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or families. Values are subject to change. Use as estimates, not for production.

Preliminary: Based on preliminary characterization. Further changes are not expected.

Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan Family Absolute Maximum Ratings(1)

Symbol	Description		Value	Units
V_{CC}	Supply voltage relative to GND		–0.5 to +7.0	V
V_{IN}	Input voltage relative to GND(2,3)		–0.5 to V_{CC} +0.5	V
V_{TS}	Voltage applied to 3-state output(2,3)		–0.5 to V_{CC} +0.5	V
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature	Plastic packages	+125	°C

Notes:
1. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
2. Maximum DC overshoot (above V_{CC}) or undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
3. Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to –2.0V or overshoot to +7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
4. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T_J = 0°C to +85°C	Commercial	4.75	5.25	V
	Supply voltage relative to GND, T_J = –40°C to +100°C(1)	Industrial	4.5	5.5	V
V_{IH}	High-level input voltage(2)	TTL inputs	2.0	V_{CC}	V
		CMOS inputs	70%	100%	V_{CC}
V_{IL}	Low-level input voltage(2)	TTL inputs	0	0.8	V
		CMOS inputs	0	20%	V_{CC}
T_{IN}	Input signal transition time		-	250	ns

Notes:
1. At junction temperatures above those listed as Recommended Operating Conditions, all delay parameters increase by 0.35% per °C.
2. Input and output measurement thresholds are: 1.5V for TTL and 2.5V for CMOS.

Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Max	Max	
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Operation Guidelines (cont.)

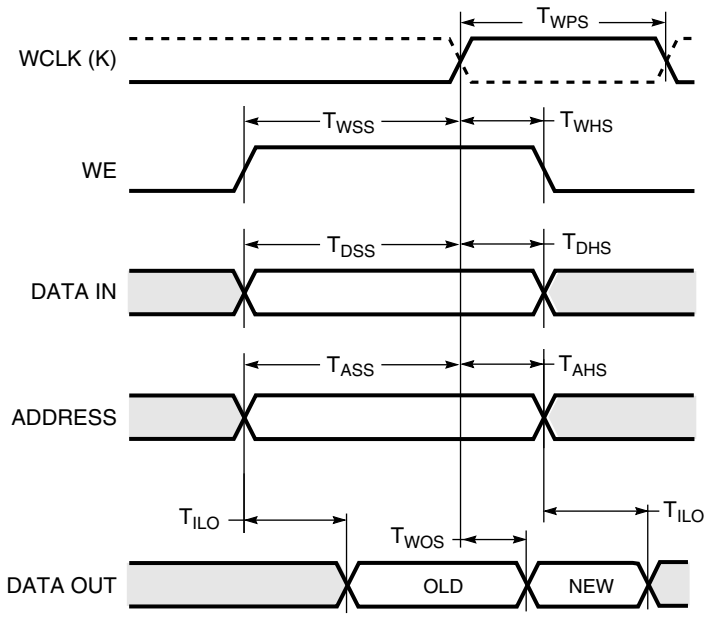
All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and are expressed in nanoseconds unless otherwise noted.

Symbol	Dual Port RAM	Size	-5		-4		Units
			Min	Max	Min	Max	
Write Operation(1)							
T_{WCDS}	Address write cycle time (clock K period)	16x1	7.7	-	8.4	-	ns
T_{WPDS}	Clock K pulse width (active edge)	16x1	3.1	-	3.6	-	ns
T_{ASDS}	Address setup time before clock K	16x1	1.3	-	1.5	-	ns
T_{DSDS}	DIN setup time before clock K	16x1	1.7	-	2.0	-	ns
T_{WSDS}	WE setup time before clock K	16x1	1.4	-	1.6	-	ns
	All hold times after clock K	16x1	0	-	0	-	ns
T_{WODS}	Data valid after clock K	16x1	-	5.2	-	6.1	ns

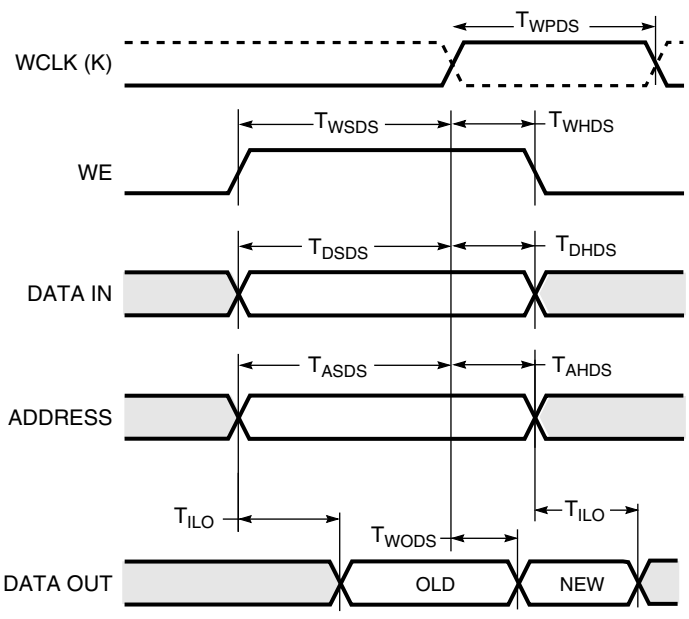
Notes:
1. Read Operation timing for 16 x 1 dual-port RAM option is identical to 16 x 2 single-port RAM timing

Spartan-XL Family CLB RAM Synchronous (Edge-Triggered) Write Timing

Single Port



Dual Port



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Spartan-XL Family IOB Input Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade				Units
			-5		-4		
			Min	Max	Min	Max	
Setup Times							
T_{ECIK}	Clock Enable (EC) to Clock (IK)	All devices	0.0	-	0.0	-	ns
T_{PICK}	Pad to Clock (IK), no delay	All devices	1.0	-	1.2	-	ns
T_{POCK}	Pad to Fast Capture Latch Enable (OK), no delay	All devices	0.7	-	0.8	-	ns
Hold Times							
	All Hold Times	All devices	0.0	-	0.0	-	ns
Propagation Delays							
T_{PID}	Pad to I1, I2	All devices	-	0.9	-	1.1	ns
T_{PLI}	Pad to I1, I2 via transparent input latch, no delay	All devices	-	2.1	-	2.5	ns
T_{IKRI}	Clock (IK) to I1, I2 (flip-flop)	All devices	-	1.0	-	1.1	ns
T_{IKLI}	Clock (IK) to I1, I2 (latch enable, active Low)	All devices	-	1.1	-	1.2	ns
Delay Adder for Input with Full Delay Option							
T_{Delay}	$T_{PICKD} = T_{PICK} + T_{Delay}$ $T_{PDLI} = T_{PLI} + T_{Delay}$	XCS05XL	4.0	-	4.7	-	ns
		XCS10XL	4.8	-	5.6	-	ns
		XCS20XL	5.0	-	5.9	-	ns
		XCS30XL	5.5	-	6.5	-	ns
		XCS40XL	6.5	-	7.6	-	ns
Global Set/Reset							
T_{MRW}	Minimum GSR pulse width	All devices	10.5	-	11.5	-	ns
T_{RRI}	Delay from GSR input to any Q	XCS05XL	-	9.0	-	10.5	ns
		XCS10XL	-	9.5	-	11.0	ns
		XCS20XL	-	10.0	-	11.5	ns
		XCS30XL	-	11.0	-	12.5	ns
		XCS40XL	-	12.0	-	13.5	ns

Notes:

1. Input pad setup and hold times are specified with respect to the internal clock (IK). For setup and hold times with respect to the clock input, see the pin-to-pin parameters in the Pin-to-Pin Input Parameters table.
2. Voltage levels of unused pads, bonded or unbonded, must be valid logic levels. Each can be configured with the internal pull-up (default) or pull-down resistor, or configured as a driven output, or can be driven from an external source.

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84[4]	VQ100	CS144[2,4]	TQ144	Bndry Scan
VCC	P33	P25	N1	P37	-
Not Connect-ed[1] PWRDWN[2]	P34	P26	N2	P38	174 [1]
I/O, PGCK2[1] GCK3[2]	P35	P27	M3	P39	175[3]
I/O (HDC)	P36	P28	N3	P40	178 [3]
I/O	-	-	K4	P41	181 [3]
I/O	-	-	L4	P42	184 [3]
I/O	-	P29	M4	P43	187 [3]
I/O ($\overline{LDC}$)	P37	P30	N4	P44	190 [3]
GND	-	-	K5	P45	-
I/O	-	-	L5	P46	193 [3]
I/O	-	-	M5	P47	196 [3]
I/O	P38	P31	N5	P48	199 [3]
I/O	P39	P32	K6	P49	202 [3]
I/O	-	P33	L6	P50	205 [3]
I/O	-	P34	M6	P51	208 [3]
I/O	P40	P35	N6	P52	211 [3]
I/O ($\overline{INIT}$)	P41	P36	M7	P53	214 [3]
VCC	P42	P37	N7	P54	-
GND	P43	P38	L7	P55	-
I/O	P44	P39	K7	P56	217 [3]
I/O	P45	P40	N8	P57	220 [3]
I/O	-	P41	M8	P58	223 [3]
I/O	-	P42	L8	P59	226 [3]
I/O	P46	P43	K8	P60	229 [3]
I/O	P47	P44	N9	P61	232 [3]
I/O	-	-	M9	P62	235 [3]
I/O	-	-	L9	P63	238 [3]
GND	-	-	K9	P64	-
I/O	P48	P45	N10	P65	241 [3]
I/O	P49	P46	M10	P66	244 [3]
I/O	-	-	L10	P67	247 [3]
I/O	-	-	N11	P68	250 [3]
I/O	P50	P47	M11	P69	253 [3]
I/O, SGCK3[1] GCK4[2]	P51	P48	L11	P70	256 [3]
GND	P52	P49	N12	P71	-
DONE	P53	P50	M12	P72	-
VCC	P54	P51	N13	P73	-
$\overline{PROGRAM}$	P55	P52	M13	P74	-
I/O (D7[2])	P56	P53	L12	P75	259 [3]

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84[4]	VQ100	CS144[2,4]	TQ144	Bndry Scan
I/O, PGCK3[1] GCK5[2]	P57	P54	L13	P76	262 [3]
I/O	-	-	K10	P77	265 [3]
I/O	-	-	K11	P78	268 [3]
I/O (D6[2])	P58	P55	K12	P79	271 [3]
I/O	-	P56	K13	P80	274 [3]
GND	-	-	J10	P81	-
I/O	-	-	J11	P82	277 [3]
I/O	-	-	J12	P83	280 [3]
I/O (D5[2])	P59	P57	J13	P84	283 [3]
I/O	P60	P58	H10	P85	286 [3]
I/O	-	P59	H11	P86	289 [3]
I/O	-	P60	H12	P87	292 [3]
I/O (D4[2])	P61	P61	H13	P88	295 [3]
I/O	P62	P62	G12	P89	298 [3]
VCC	P63	P63	G13	P90	-
GND	P64	P64	G11	P91	-
I/O (D3[2])	P65	P65	G10	P92	301 [3]
I/O	P66	P66	F13	P93	304 [3]
I/O	-	P67	F12	P94	307 [3]
I/O	-	-	F11	P95	310 [3]
I/O (D2[2])	P67	P68	F10	P96	313 [3]
I/O	P68	P69	E13	P97	316 [3]
I/O	-	-	E12	P98	319 [3]
I/O	-	-	E11	P99	322 [3]
GND	-	-	E10	P100	-
I/O (D1[2])	P69	P70	D13	P101	325 [3]
I/O	P70	P71	D12	P102	328 [3]
I/O	-	-	D11	P103	331 [3]
I/O	-	-	C13	P104	334 [3]
I/O (D0[2], DIN)	P71	P72	C12	P105	337 [3]
I/O, SGCK4[1] GCK6[2] (DOUT)	P72	P73	C11	P106	340 [3]
CCLK	P73	P74	B13	P107	-
VCC	P74	P75	B12	P108	-
O, TDO	P75	P76	A13	P109	0
GND	P76	P77	A12	P110	-
I/O	P77	P78	B11	P111	2
I/O, PGCK4[1] GCK7[2]	P78	P79	A11	P112	5
I/O	-	-	D10	P113	8
I/O	-	-	C10	P114	11
I/O (CS1[2])	P79	P80	B10	P115	14

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
PROGRAM	P52	M13	P74	P106	-
I/O (D7[2])	P53	L12	P75	P107	367 [3]
I/O, PGCK3[1], GCK5[2]	P54	L13	P76	P108	370 [3]
I/O	-	K10	P77	P109	373 [3]
I/O	-	K11	P78	P110	376 [3]
I/O (D6[2])	P55	K12	P79	P112	379 [3]
I/O	P56	K13	P80	P113	382 [3]
I/O	-	-	-	P114	385 [3]
I/O	-	-	-	P115	388 [3]
I/O	-	-	-	P116	391 [3]
I/O	-	-	-	P117	394 [3]
GND	-	J10	P81	P118	-
I/O	-	J11	P82	P119	397 [3]
I/O	-	J12	P83	P120	400 [3]
VCC[2]	-	-	-	P121	-
I/O (D5[2])	P57	J13	P84	P122	403 [3]
I/O	P58	H10	P85	P123	406 [3]
I/O	-	-	-	P124	409 [3]
I/O	-	-	-	P125	412 [3]
I/O	P59	H11	P86	P126	415 [3]
I/O	P60	H12	P87	P127	418 [3]
I/O (D4[2])	P61	H13	P88	P128	421 [3]
I/O	P62	G12	P89	P129	424 [3]
VCC	P63	G13	P90	P130	-
GND	P64	G11	P91	P131	-
I/O (D3[2])	P65	G10	P92	P132	427 [3]
I/O	P66	F13	P93	P133	430 [3]
I/O	P67	F12	P94	P134	433 [3]
I/O	-	F11	P95	P135	436 [3]
I/O	-	-	-	P136	439 [3]
I/O	-	-	-	P137	442 [3]
I/O (D2[2])	P68	F10	P96	P138	445 [3]
I/O	P69	E13	P97	P139	448 [3]
VCC[2]	-	-	-	P140	-
I/O	-	E12	P98	P141	451 [3]
I/O	-	E11	P99	P142	454 [3]
GND	-	E10	P100	P143	-
I/O	-	-	-	P145	457 [3]
I/O	-	-	-	P146	460 [3]
I/O	-	-	-	P147	463 [3]
I/O	-	-	-	P148	466 [3]
I/O (D1[2])	P70	D13	P101	P149	469 [3]
I/O	P71	D12	P102	P150	472 [3]
I/O	-	D11	P103	P151	475 [3]

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
I/O	-	C13	P104	P152	478 [3]
I/O (D0[2], DIN)	P72	C12	P105	P153	481 [3]
I/O, SGCK4[1], GCK6[2] (DOUT)	P73	C11	P106	P154	484 [3]
CCLK	P74	B13	P107	P155	-
VCC	P75	B12	P108	P156	-
O, TDO	P76	A13	P109	P157	0
GND	P77	A12	P110	P158	-
I/O	P78	B11	P111	P159	2
I/O, PGCK4[1], GCK7[2]	P79	A11	P112	P160	5
I/O	-	D10	P113	P161	8
I/O	-	C10	P114	P162	11
I/O (CS1[2])	P80	B10	P115	P163	14
I/O	P81	A10	P116	P164	17
I/O	-	D9	P117	P166	20
I/O	-	-	-	P167	23
I/O	-	-	-	P168	26
I/O	-	-	-	P169	29
GND	-	C9	P118	P170	-
I/O	-	B9	P119	P171	32
I/O	-	A9	P120	P172	35
VCC[2]	-	-	-	P173	-
I/O	P82	D8	P121	P174	38
I/O	P83	C8	P122	P175	41
I/O	-	-	-	P176	44
I/O	-	-	-	P177	47
I/O	P84	B8	P123	P178	50
I/O	P85	A8	P124	P179	53
I/O	P86	B7	P125	P180	56
I/O	P87	A7	P126	P181	59
GND	P88	C7	P127	P182	-

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XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	-	-	P124	P144	M20	L19	493 [3]
I/O	-	-	P125	P145	L19	L18	496 [3]
I/O	P59	P86	P126	P146	L18	L17	499 [3]
I/O	P60	P87	P127	P147	L20	L16	502 [3]
I/O (D4[2])	P61	P88	P128	P148	K20	K19	505 [3]
I/O	P62	P89	P129	P149	K19	K18	508 [3]
VCC	P63	P90	P130	P150	VCC[4]	K17	-
GND	P64	P91	P131	P151	GND[4]	GND[4]	-
I/O (D3[2])	P65	P92	P132	P152	K18	K16	511 [3]
I/O	P66	P93	P133	P153	K17	K15	514 [3]
I/O	P67	P94	P134	P154	J20	J19	517 [3]
I/O	-	P95	P135	P155	J19	J18	520 [3]
I/O	-	-	P136	P156	J18	J17	523 [3]
I/O	-	-	P137	P157	J17	J16	526 [3]
I/O (D2[2])	P68	P96	P138	P159	H19	H17	529 [3]
I/O	P69	P97	P139	P160	H18	H16	532 [3]
VCC	-	-	P140	P161	VCC[4]	G19	-
I/O	-	P98	P141	P162	G19	G18	535 [3]
I/O	-	P99	P142	P163	F20	G17	538 [3]
I/O	-	-	-	P164	G18	G16	541 [3]
I/O	-	-	-	P165	F19	F19	544 [3]
GND	-	P100	P143	P166	GND[4]	GND[4]	-
I/O	-	-	-	P167	F18	F18	547 [3]
I/O	-	-	P144	P168	E19	F17	550 [3]
I/O	-	-	P145	P169	D20	F16	553 [3]
I/O	-	-	P146	P170	E18	F15	556 [3]
I/O	-	-	P147	P171	D19	E19	559 [3]
I/O	-	-	P148	P172	C20	E17	562 [3]
I/O (D1[2])	P70	P101	P149	P173	E17	E16	565 [3]
I/O	P71	P102	P150	P174	D18	D19	568 [3]
I/O	-	P103	P151	P175	C19	C19	571 [3]
I/O	-	P104	P152	P176	B20	B19	574 [3]
I/O (D0[2], DIN)	P72	P105	P153	P177	C18	C18	577 [3]
I/O, SGCK4[1], GCK6[2] (DOUT)	P73	P106	P154	P178	B19	B18	580 [3]
CCLK	P74	P107	P155	P179	A20	A19	-
VCC	P75	P108	P156	P180	VCC[4]	C17	-
O, TDO	P76	P109	P157	P181	A19	B17	0
GND	P77	P110	P158	P182	GND[4]	GND[4]	-
I/O	P78	P111	P159	P183	B18	A18	2
I/O, PGCK4[1], GCK7[2]	P79	P112	P160	P184	B17	A17	5
I/O	-	P113	P161	P185	C17	D16	8
I/O	-	P114	P162	P186	D16	C16	11
I/O (CS1)[2]	P80	P115	P163	P187	A18	B16	14
I/O	P81	P116	P164	P188	A17	A16	17
I/O	-	-	P165	P189	C16	D15	20

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	-	-	-	P190	B16	A15	23
I/O	-	P117	P166	P191	A16	E14	26
I/O	-	-	P167	P192	C15	C14	29
I/O	-	-	P168	P193	B15	B14	32
I/O	-	-	P169	P194	A15	D14	35
GND	-	P118	P170	P196	GND[4]	GND[4]	-
I/O	-	P119	P171	P197	B14	A14	38
I/O	-	P120	P172	P198	A14	C13	41
I/O	-	-	-	P199	C13	B13	44
I/O	-	-	-	P200	B13	A13	47
VCC	-	-	P173	P201	VCC[4]	D13	-
I/O	P82	P121	P174	P202	C12	B12	50
I/O	P83	P122	P175	P203	B12	D12	53
I/O	-	-	P176	P205	A12	A11	56
I/O	-	-	P177	P206	B11	B11	59
I/O	P84	P123	P178	P207	C11	C11	62
I/O	P85	P124	P179	P208	A11	D11	65
I/O	P86	P125	P180	P209	A10	A10	68
I/O	P87	P126	P181	P210	B10	B10	71
GND	P88	P127	P182	P211	GND[4]	GND[4]	-

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Notes:
1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS30XL is not part of the Boundary Scan chain. For the XCS30XL, subtract 1 from all Boundary Scan numbers from GCK3 on (295 and higher).
4. Pads labeled GND[4] or V_{CC}[4] are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package, and VQ100 and BG256 packages for XCS30 only, discontinued by PDN2004-01

Additional XCS30/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-
Not Connected Pins					
A7	A13	C8	D12	H20	J3
J4	M4	M19	V9	W9	W13
Y13	-	-	-	-	-

6/4/97

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-

CS280

VCC Pins					
A1	A7	C10	C17	D13	G1
G1	G19	K2	K17	M4	N16
T7	U3	U10	U17	W13	-
GND Pins					

XCS40 and XCS40XL Device Pinouts

XCS40/XL Pad Name	PQ208	PQ240	BG256	CS280[2,5]	Bndry Scan
O, TDO	P157	P181	A19	B17	0
GND	P158	P182	GND[4]	GND[4]	-
I/O	P159	P183	B18	A18	2
I/O, PGCK4[1], GCK7[2]	P160	P184	B17	A17	5
I/O	P161	P185	C17	D16	8
I/O	P162	P186	D16	C16	11
I/O (CS1[2])	P163	P187	A18	B16	14
I/O	P164	P188	A17	A16	17
I/O	-	-	-	E15	20
I/O	-	-	-	C15	23
I/O	P165	P189	C16	D15	26
I/O	-	P190	B16	A15	29
I/O	P166	P191	A16	E14	32
I/O	P167	P192	C15	C14	35
I/O	P168	P193	B15	B14	38
I/O	P169	P194	A15	D14	41
GND	P170	P196	GND[4]	GND[4]	-
I/O	P171	P197	B14	A14	44
I/O	P172	P198	A14	C13	47
I/O	-	P199	C13	B13	50
I/O	-	P200	B13	A13	53
VCC	P173	P201	VCC[4]	VCC[4]	-
I/O	-	-	A13	A12	56
I/O	-	-	D12	C12	59
I/O	P174	P202	C12	B12	62
I/O	P175	P203	B12	D12	65
I/O	P176	P205	A12	A11	68
I/O	P177	P206	B11	B11	71
I/O	P178	P207	C11	C11	74
I/O	P179	P208	A11	D11	77
I/O	P180	P209	A10	A10	80
I/O	P181	P210	B10	B10	83
GND	P182	P211	GND[4]	GND[4]	-

2/8/00

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS40XL is not part of the Boundary Scan chain. For the XCS40XL, subtract 1 from all Boundary Scan numbers from GCK3 on (343 and higher).
4. Pads labeled GND[4] or V_{CC}[4] are internally bonded to Ground or V_{CC} planes within the package.
5. CS280 package discontinued by PDN2004-01

Additional XCS40/XL Package Pins

PQ240

GND Pins					
P22	P37	P83	P98	P143	P158
P204	P219	-	-	-	-
Not Connected Pins					
P195	-	-	-	-	-

2/12/98

BG256

VCC Pins					
C14	D6	D7	D11	D14	D15
E20	F1	F4	F17	G4	G17
K4	L17	P4	P17	P19	R2
R4	R17	U6	U7	U10	U14
U15	V7	W20	-	-	-
GND Pins					
A1	B7	D4	D8	D13	D17
G20	H4	H17	N3	N4	N17
U4	U8	U13	U17	W14	-

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CS280

VCC Pins					
A1	A7	B5	B15	C10	C17
D13	E3	E18	G1	G19	K2
K17	M4	N16	R3	R18	T7
U3	U10	U17	V5	V15	W13
GND Pins					
E5	E7	E8	E9	E11	E12
E13	G5	G15	H5	H15	J5
J15	L5	L15	M5	M15	N5
N15	R7	R8	R9	R11	R12
R13	-	-	-	-	-

5/19/99

Table 20: **User I/O Chart for Spartan/XL FPGAs**

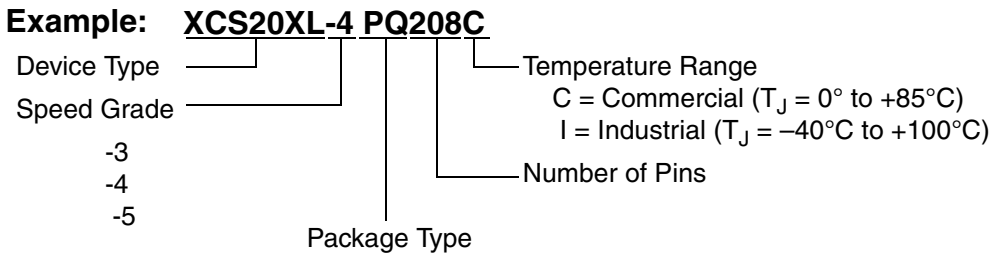
Device	Max I/O	Package Type							
		PC84(1)	VQ100(1)	CS144(1)	TQ144	PQ208	PQ240	BG256(1)	CS280(1)
XCS05	80	61(1)	77	-	-	-	-	-	-
XCS10	112	61(1)	77	-	112	-	-	-	-
XCS20	160	-	77	-	113	160	-	-	-
XCS30	192	-	77(1)	-	113	169	192	192(1)	-
XCS40	224	-	-	-	-	169	192	205	-
XCS05XL	80	61(1)	77(2)	-	-	-	-	-	-
XCS10XL	112	61(1)	77(2)	112(1)	112(2)	-	-	-	-
XCS20XL	160	-	77(2)	113(1)	113(2)	160(2)	-	-	-
XCS30XL	192	-	77(2)	-	113(2)	169(2)	192(2)	192(2)	192(1)
XCS40XL	224	-	-	-	-	169(2)	192(2)	205(2)	224(1)

6/25/08

Notes:

1. PC84, CS144, and CS280 packages, and VQ100 and BG256 packages for XCS30 only, discontinued by PDN2004-01
2. These Spartan-XL devices are available in Pb-free package options. The Pb-free packages insert a "G" in the package code. Contact Xilinx for availability.

Ordering Information



BG = Ball Grid Array
BGG = Ball Grid Array (Pb-free)
PC = Plastic Lead Chip Carrier
PQ = Plastic Quad Flat Pack
PQG = Plastic Quad Flat Pack (Pb-free)
VQ = Very Thin Quad Flat Pack
VQG = Very Thin Quad Flat Pack (Pb-free)
TQ = Thin Quad Flat Pack
TQG = Thin Quad Flat Pack (Pb-free)
CS = Chip Scale